



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

2877⁶ 6.13.2

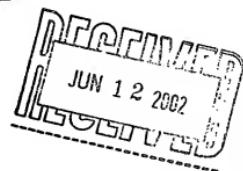
Applicant: Adam E. Norton et al. PATENT APPLICATION
Serial No.: 10/081,078 Group Art Unit: 2877
Filed: February 21, 2002 Examiner:
For: SMALL-SPOT SPECTROMETRY INSTRUMENT WITH
REDUCED POLARIZATION AND MULTIPLE-ELEMENT
DEPOLARIZER THEREFOR

Information Disclosure Statement

Hon. Assistant Commissioner
for Patents
Washington, D.C. 20231

Sir:

The following information is submitted in
compliance with Applicants' duty of disclosure under 37
CFR § 1.56. A copy of each reference is enclosed.



<u>Pat. No.</u>	<u>Patentee</u>	<u>Grant Date</u>	RECEIVED
4,572,608	Mochizuki et al.	02/25/86	JUN 10 2002
4,922,309	Sekiwa et al.	05/01/90	TC 2800 MAIL ROOM
5,218,652	Lutz	06/08/93	
5,371,595	Nishiura et al.	12/06/94	
5,430,795	Taga et al.	07/04/95	
5,933,555	Shen	08/03/99	
6,040,906	Harhay	03/21/00	

Other References

M.E. Lee et al., "Analysis of Reflectometry and
Ellipsometry Data from Patterned Structures", Dept. of
Electrical Engineering and Computer Science, Univ. of
Michigan, MI, 5 pages.

Nasa Research Announcement, "Technical Details on OMI and Other EOS Chem Instruments", Sept. 29, 1999, 2 pages.

Varian Inc. paper, Scientific Instruments, "Polarizer and Depolarizer Accessory", June 28, 2000, 2 pages.

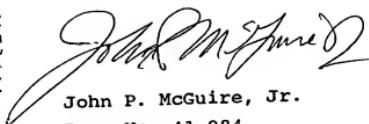
CERTIFICATE OF MAILING

I hereby certify that this paper (along with any paper referred to as being attached or enclosed) is being deposited with the United States Postal Service on the date shown below with sufficient postage as first class mail in an envelope addressed to: Asst. Commissioner for Patents, Washington, D.C. 20231

Signed: Sally Azevedo
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Respectfully submitted,



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FORM PTO-1449

LIST OF PRIOR ART
CITED BY APPLICANTAtty. Docket No.
SEN-020 Serial No.
10/081,078Applicant:
Adam E. Norton et al.Filing Date:
February 21, 2002 Group:
2877

U.S. PATENT DOCUMENTS

Examiner Initial*	Document Number	Grant Date	Name	Class	Sub Class	Filing Date
AA	4,572,608	02/25/86	Mochizuki et al.	350	96.15	
AB	4,922,309	05/01/90	Sekiwa et al.	356	300	
AC	5,218,652	06/08/93	Lutz	385	11	
AD	5,371,595	12/06/94	Nishiura et al.	356	350	
AE	5,430,795	07/04/95	Taga et al.	359	179	
AF	5,933,555	08/03/99	Shen	385	32	
AG	6,040,906	03/21/00	Harhay	356	301	
AH						IC 2800
AI						JUN 10
AJ						RECEIVED MAIL 2002

FOREIGN PATENT DOCUMENTS

Examiner Initial*	Document Number	Grant Date	Country	Class	Sub Class	ROUTINE	TRANSLATION	Yes	No
AK									
AL									

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AM	M.E. Lee et al., "Analysis of Reflectometry and Ellipsometry Data from Patterned Structures", Dept. of Electrical Engineering and Computer Science, Univ. of Michigan, MI, 5 pages.
AN	Nasa Research Announcement, "Technical Details on OMI and Other EOS Chem Instruments", Sept. 29, 1999, 2 pages.
AO	Varian Inc. paper, Scientific Instruments, "Polarizer and Depolarizer Accessory", June 28, 2000, 2 pages.

EXAMINER:

DATE CONSIDERED:

*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.